



# Development of Hybrid Avalanche Photo Detector and its Readout Electronics for the Belle II Aerogel RICH counter

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(Belle II Aerogel RICH group)

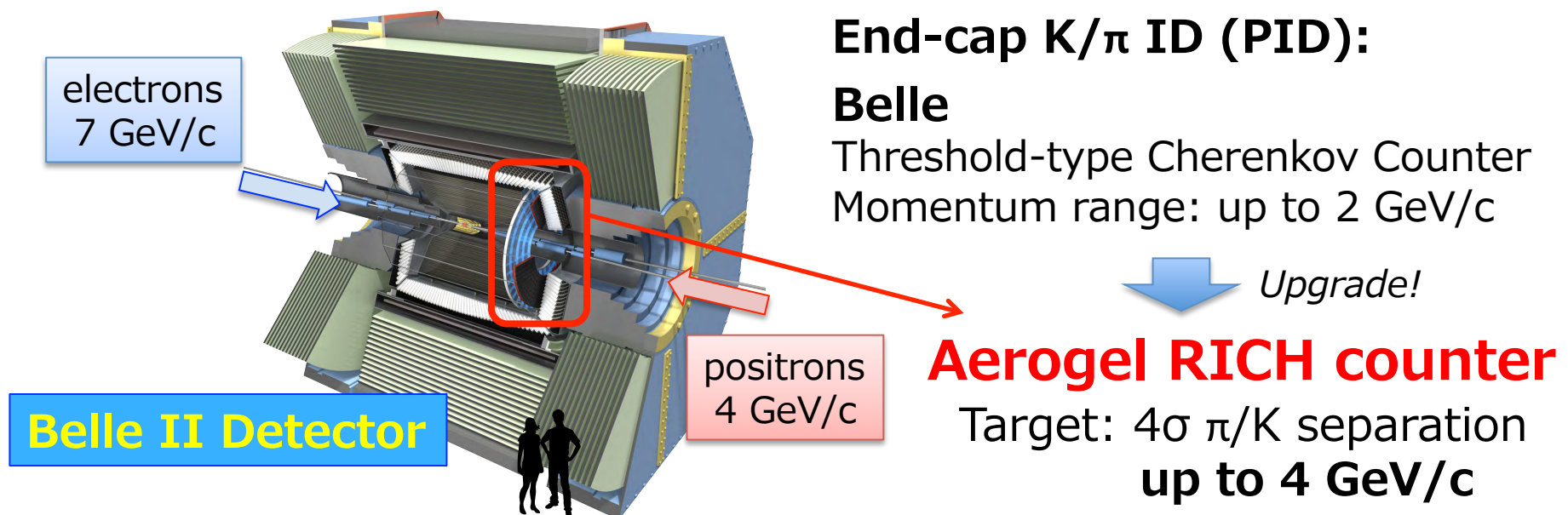
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- Introduction
- Status of Development
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  - Readout ASIC
  - Related Electronics
- Summary

# Belle II experiment

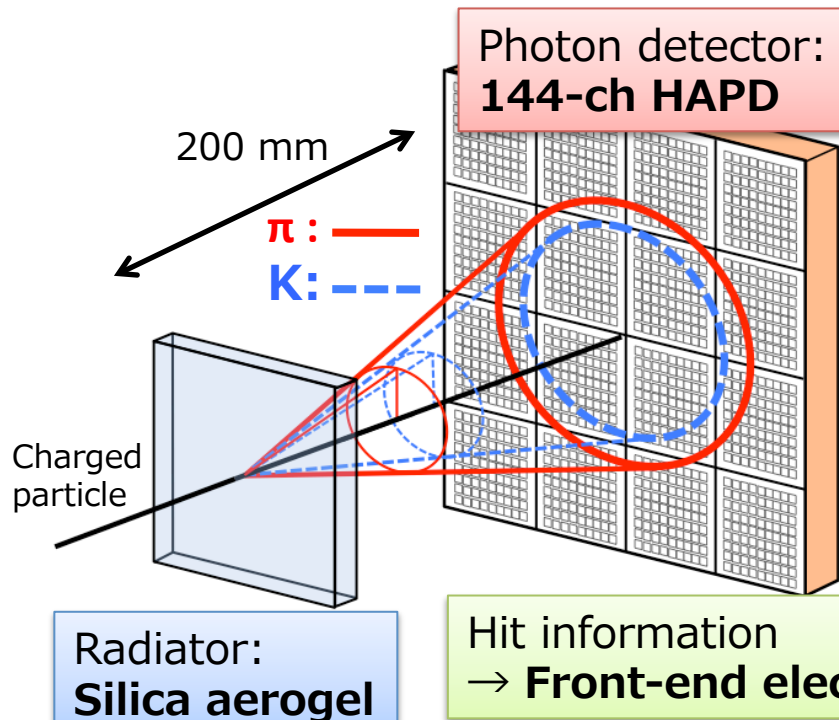
- **Belle experiment**
  - KEKB accelerator/Belle detector: B-Factory experiment
  - Discovery of CP Violation in B system
  - Verification of Kobayashi-Maskawa mechanism
  - Finished in 2010.6
- **Upgrade to SuperKEKB accelerator / Belle II detector**
  - Integrated Luminosity:  $50 \text{ ab}^{-1}$
  - Physics Goal: Search for New Physics



# Aerogel RICH (A-RICH)

Proximity-Focusing **R**ing **I**maging **C**herenkov counter using **aerogel** as radiator

## Principle of A-RICH



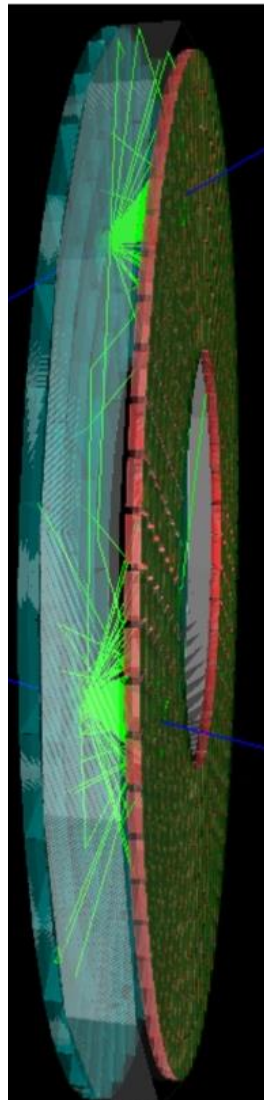
1. Produce Cherenkov light in the **aerogel**.
2. Detect photons as a ring image using a position sensitive detector array.
3. The radiation angle  $\theta_C$  is calculated.
4. K/ $\pi$  ID is performed by the equation:

$$m = \frac{p}{c} \sqrt{n^2 \cos^2 \theta_C - 1}$$

$$\Delta\theta_C = \theta_C(\pi) - \theta_C(K) \simeq 23 \text{ mrad}$$

$$\text{@ } 4 \text{ GeV}/c, n = 1.05$$

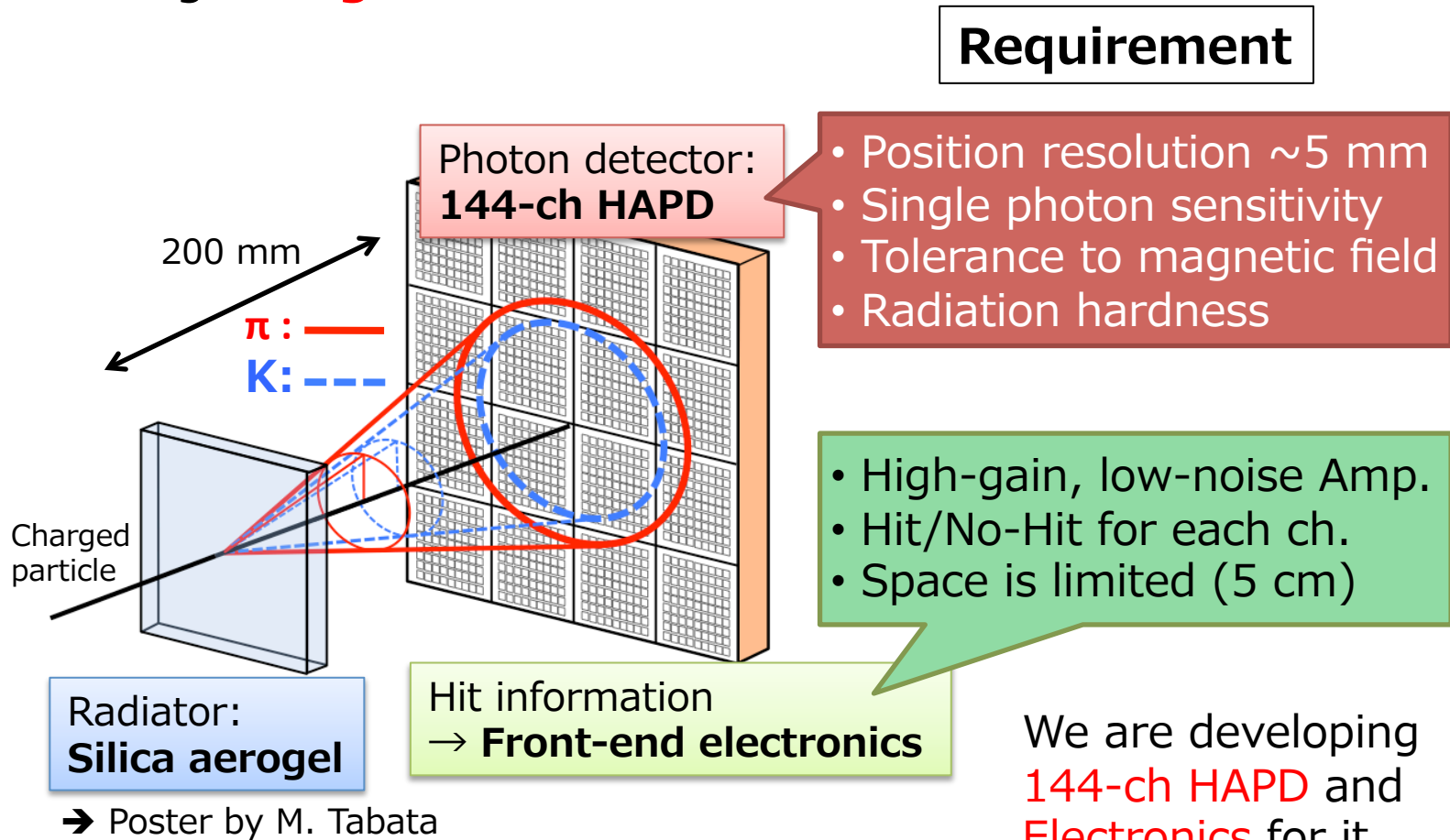
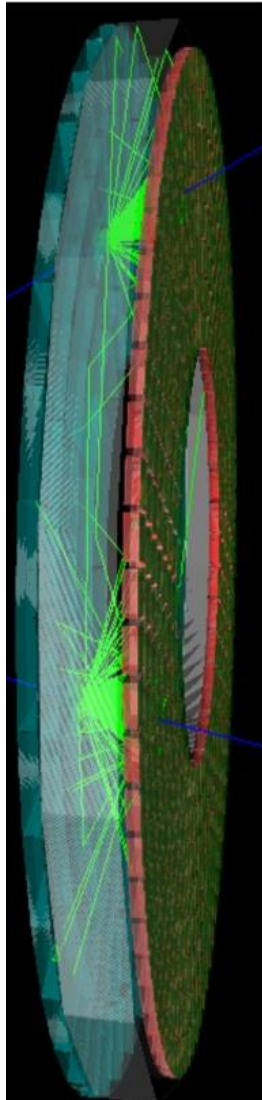
→ Poster by M. Tabata





# Aerogel RICH (A-RICH)

Proximity-Focusing **R**ing **I**maging **C**herenkov counter using **aerogel** as radiator



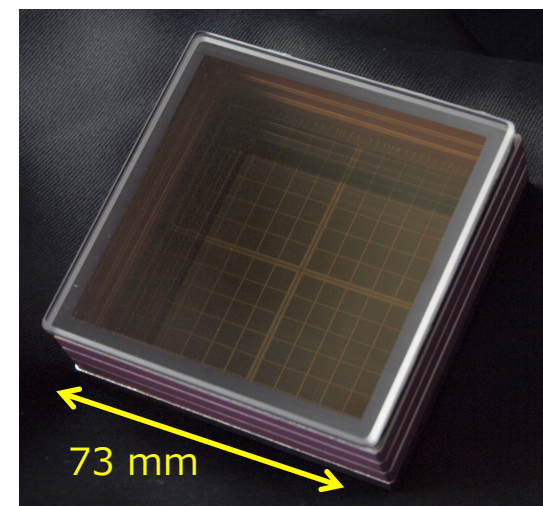
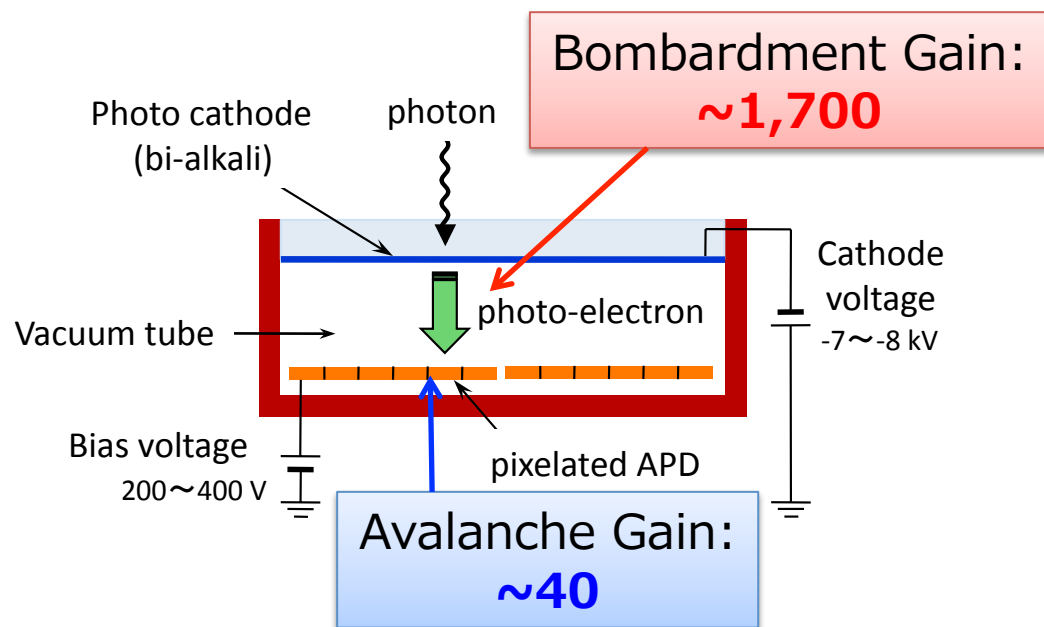
# 144-ch HAPD

Hybrid **A**valanche **P**hoto-**D**etector

We have been developing the HAPD with Hamamatsu Photonics K.K. since 2002.

420 modules will be installed in Belle II.

## Structure of the HAPD



## Specification

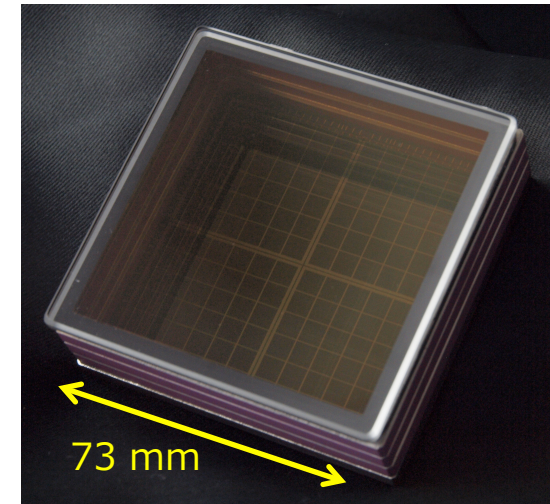
# of channel	$12 \times 12 = 144$
tube size	$73 \times 73 \text{ mm}^2$
effective area	$\sim 65\%$
pixel size	$4.9 \times 4.9 \text{ mm}^2$
APD capacitance	80 pF
typical QE	28% @400 nm
Total gain	$\sim 7 \times 10^4$

# 144-ch HAPD

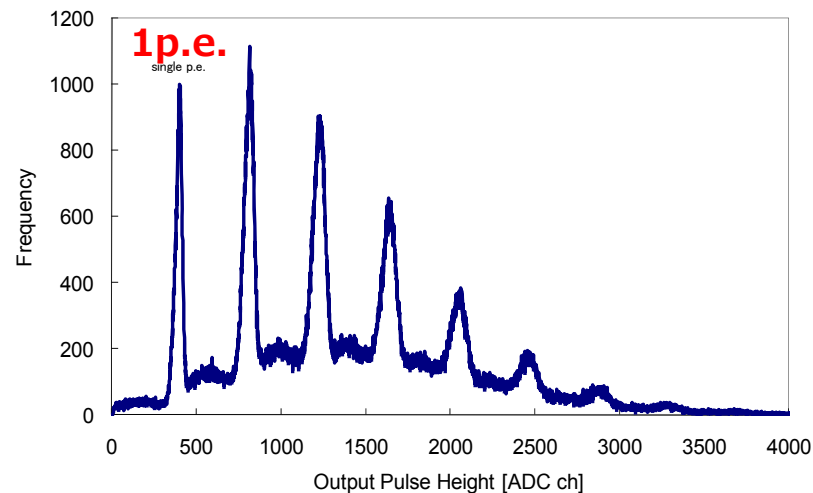
Hybrid **A**valanche **P**hoto-**D**etector

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**420** modules will be installed in Belle II.



Pulse height distribution



Good single photon separation in every pixel.

Specification

# of channel	$12 \times 12 = 144$
tube size	$73 \times 73 \text{ mm}^2$
effective area	<b><math>\sim 65\%</math></b>
pixel size	<b><math>4.9 \times 4.9 \text{ mm}^2</math></b>
APD capacitance	80 pF
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# Radiation Hardness of HAPD

HAPDs will be used in radiation environment for **10 years** operation.

**Neutrons:**  $1 \times 10^{12}$  neutrons/cm<sup>2</sup> (1 MeV equiv.)

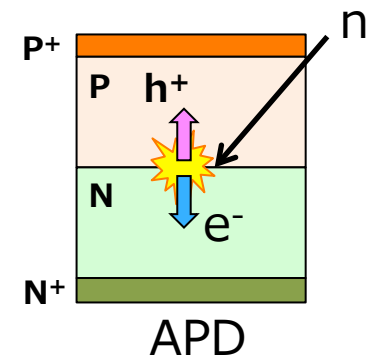
Neutrons induce **lattice defects** in APD bulk region.  
They cause **increasing leakage current**.

→ **S/N** become worse

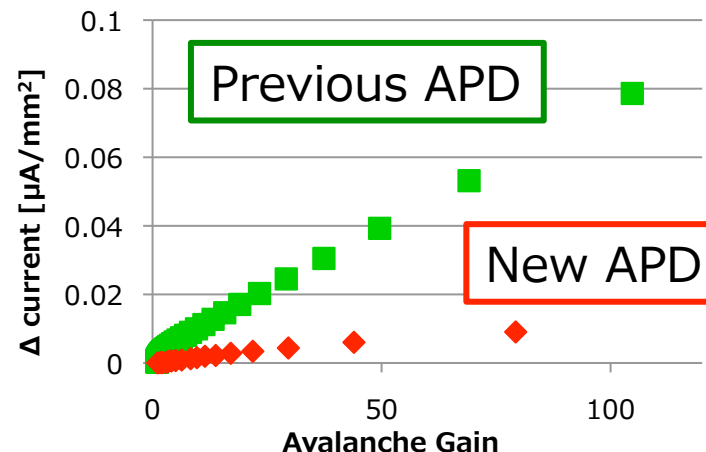
We changed **P and P+ layer** structure in APD.

Thinner **P** : To **suppress** increase of current.

Thinner **P+** : To **improve** bombardment gain.



We confirmed thinner P layer can suppress increase of leakage current.



## History of radiation test

2011: Thinner P/P+ layer

2012~2013:

Production type is irradiated with expected neutron flux

# Radiation Hardness of HAPD

HAPDs will be used in radiation environment for **10 years** operation.

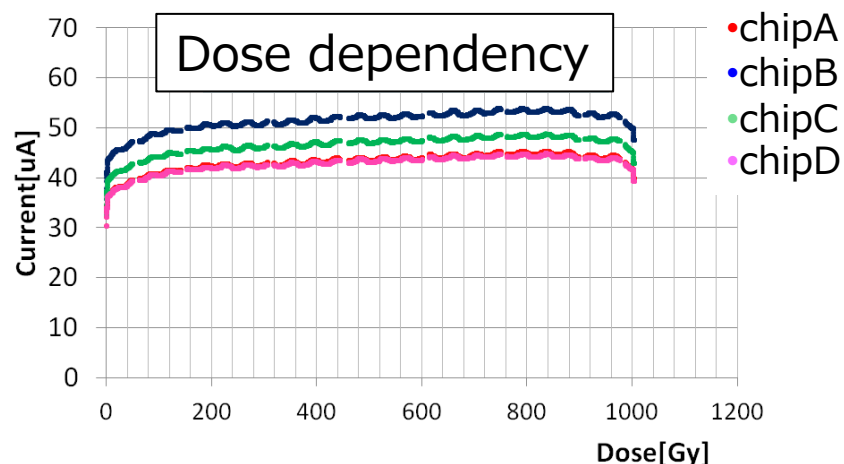
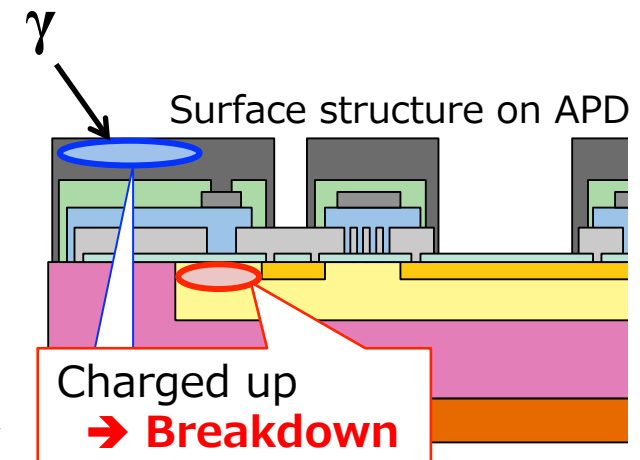
## Gamma-ray: 1 kGy

**Charge-up** around the structure on APD surface occurred by gamma-ray.

**Breakdown voltage is degraded.**

→ lowers **Avalanche gain**.

We changed surface structure on APD to prevent it, and carried out radiation tests after neutron test.



Breakdown is not observed up to **1 kGy** radiation.

Trial samples have sufficient **neutron and gamma radiation hardness** for Belle II.



# Readout Electronics

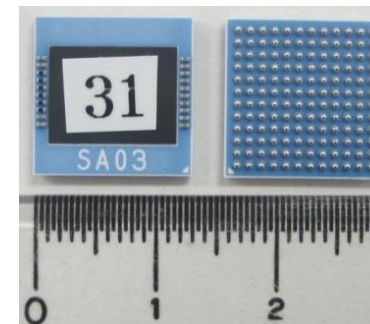
- High-gain, low-noise Amp.
- Hit/No-Hit information
- Space is limited



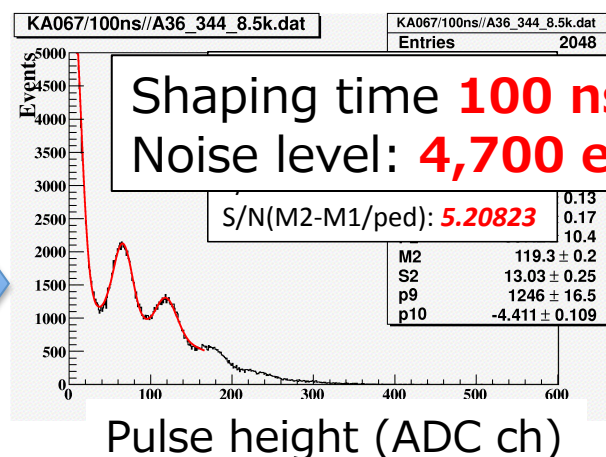
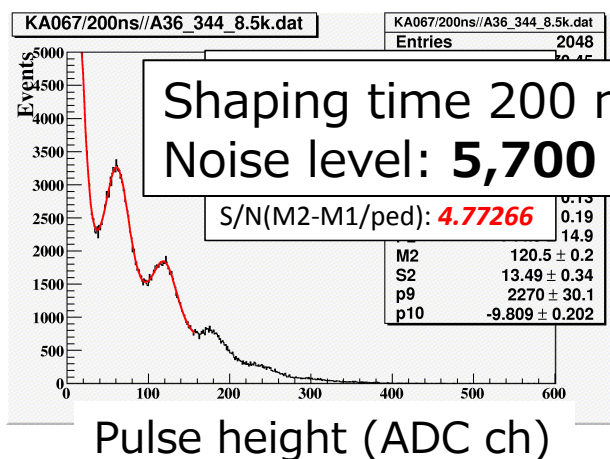
We developed **original ASIC** and **related circuit** for A-RICH.

## • Readout ASIC

- 36 channels/chip (=4 chips for 1 HAPD)
- variable shaping time
  - 100~200 ns for noise reduction due to neutron irradiation



Neutron test in 2013



We confirmed noise reduction with **shorter shaping time**.

# Readout Electronics

- High-gain, low-noise Amp.
- Hit/No-Hit information
- Space is limited



We developed **original ASIC** and **related circuit** for A-RICH.

- **Readout ASIC**

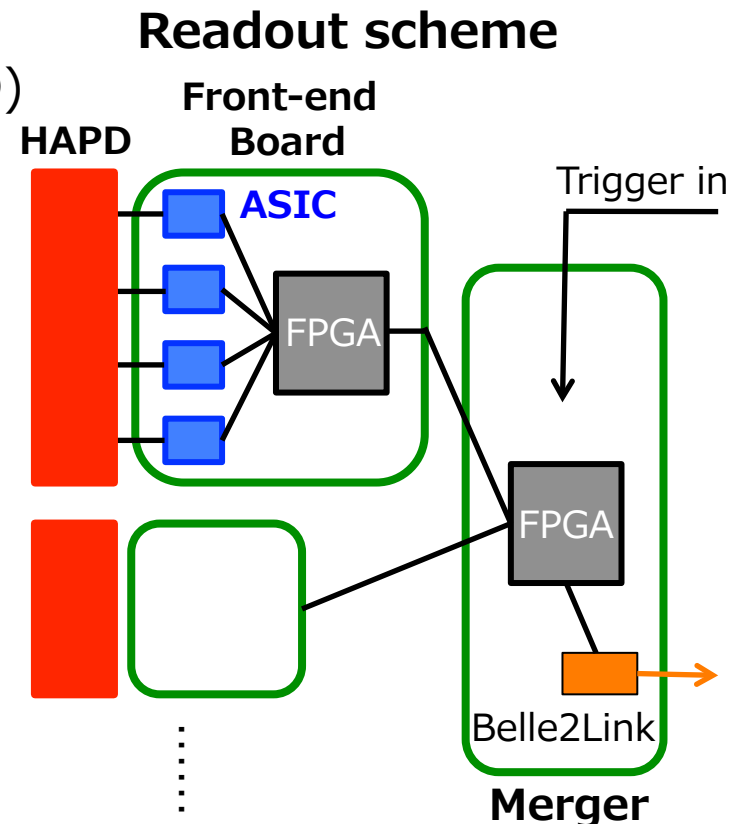
- 36 channels/chip (=4 chips for 1 HAPD)
- variable shaping time
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- **Front-end board**

- FPGA
  - Process Digital hit signals treatment
  - Setting ASIC parameters

- **Merger system**

- Merge data from 5~6 FE board
- Suppress size of signals







# **Status of Development**

# HAPD

- Mass production already started in 2013.
  - **420**(main)+Spare = 450 in total
  - Delivery Schedule
    - Aug. 2013 ~ Sep. 2014
    - 30 ~ 40 samples every month
- Quality check is on-going at KEK.
  - **Quantum Efficiency (QE)**
  - **Dead channel check**
    - Leakage current
    - Noise level
    - Gain
    - 2D Hit-map

## QE Measurement Result

Requirement	Measured (Average)
28% (Typically) >24%	<b>30.0%</b> (RMS 3.7%)

(#samples = 193)

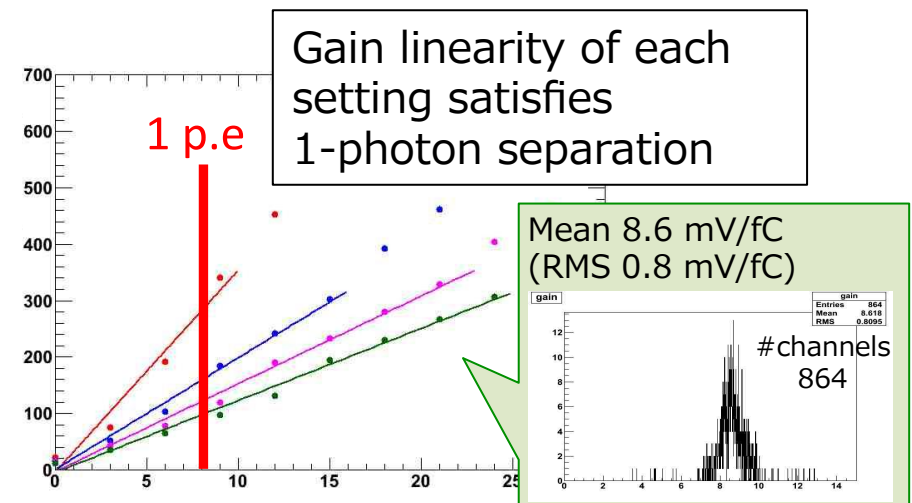
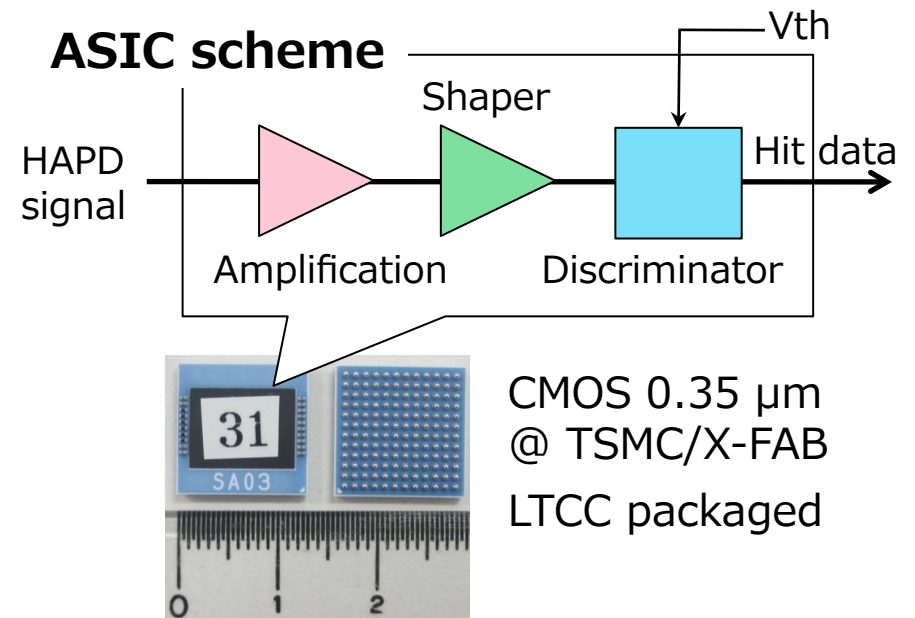
## Good Sample Selection

	#HAPDs
<b>Good</b>	<b>134 (86%)</b>
Low Quality	5 (3%)
Under Investigation	15 (10%)
Rejected	2 (1%)
Checked (Total)	156

(Mar. 2014)

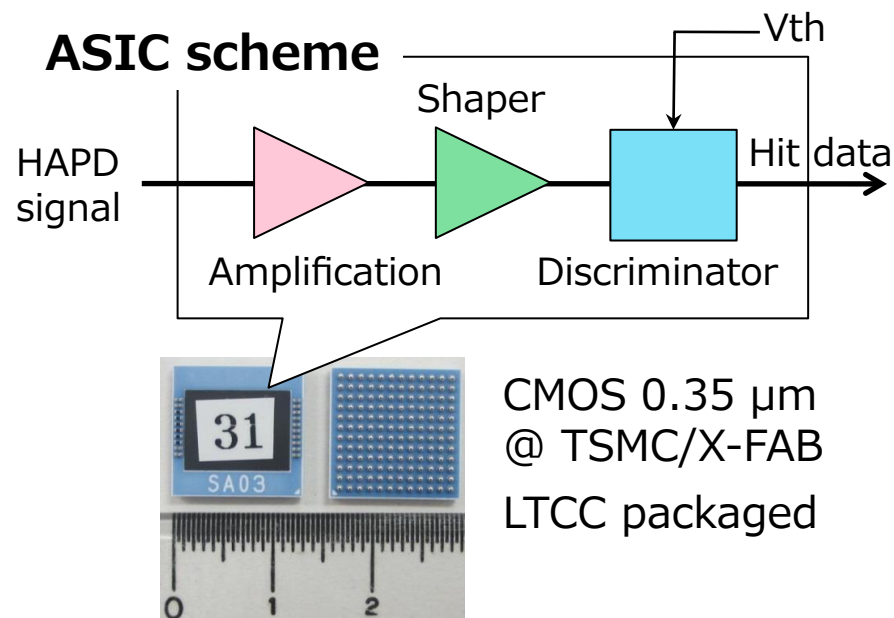
# Readout ASIC

- The ASIC is designed in order to satisfy our requirement.
- ASIC production had been finished.
  - **2,500** samples had been produced.
- We will choose good chips from them.
  - **1,680** chips are needed.
  - **Test system** is developed for this purpose.



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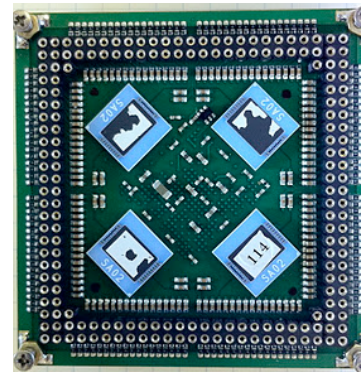
Dead channel Appearance

Tested	Dead
6,480 ch. (= 180 chips)	<b>47 ch.</b> (in 30 chips)

# Related Electronics

- **Front-end board**
  - 4 ASIC and FPGA
  - The final version is under designing

Connector side



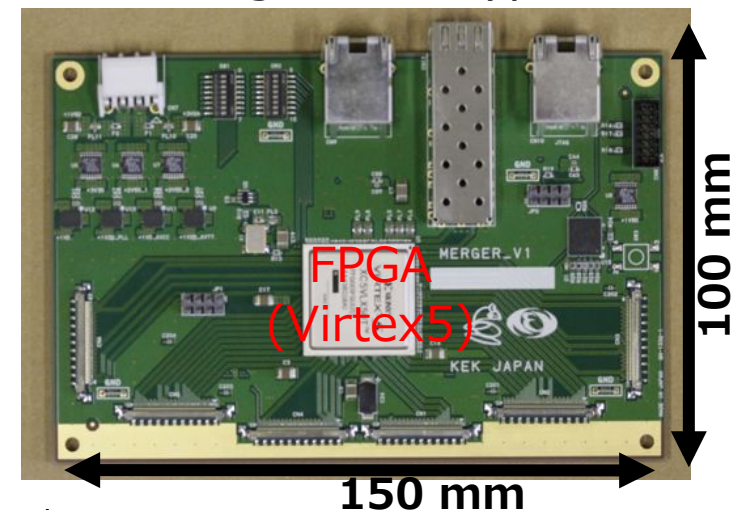
Attached on HAPD



- **Merger system**

- Designing the final version.
  - Merge data from 5-6 HAPDs
  - Send data to central DAQ
  - Trigger/clock distribution
  - Configuration for the front-end
- Communication test is on-going with prototype.

Merger Prototype



# Mass Production Status

- **HAPD:**
  - Delivery is delayed about a few months.
  - Quality check of delivered HAPDs are mostly done.

## ❖ Investigation of Noisy Sample

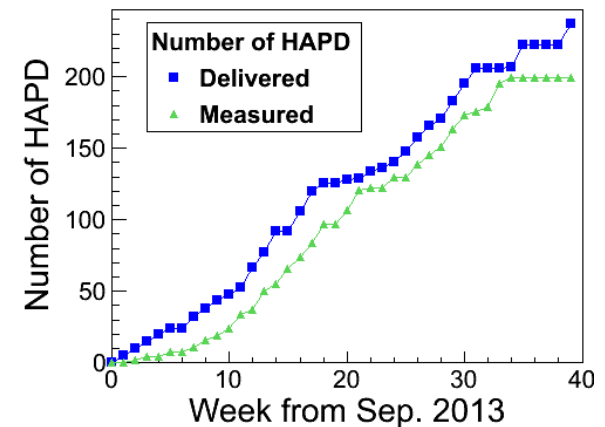
We found some samples are noisy in 2D hit-map.

This noise occurred **after light exposure**.

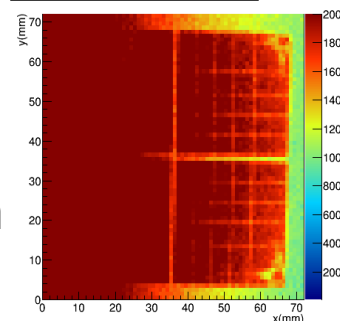
Noise in most samples of this reason **disappear in ~30 min after light exposure and HV ON.**

→ ~30 min: **10** samples, >1hour: **7** samples

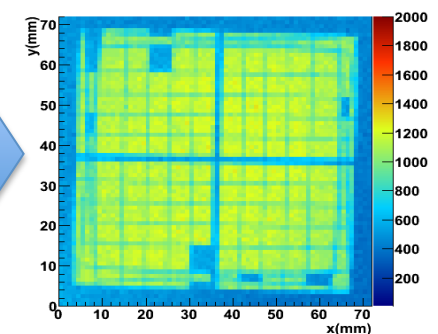
Trends of HAPD Production



Noisy sample



30min after HV ON

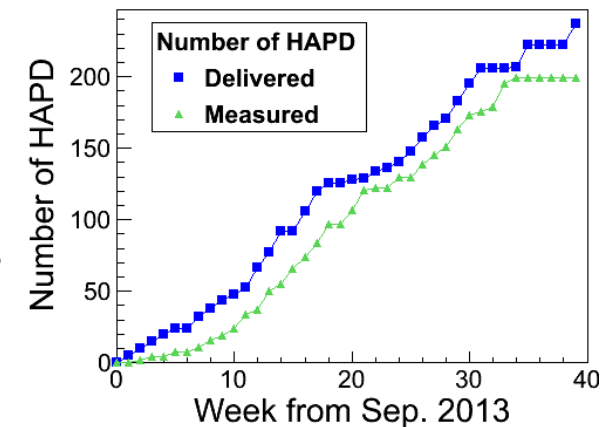


Noise disappeared

# Mass Production Status

- **HAPD:**
  - Delivery is delayed about a few months.
  - Quality check of delivered HAPDs are mostly done.
- **Electronics:**
  - The ASIC production was finished.
  - Quality check is on-going.
    - We developed the **test system** for produced ASICs.
  - Front-end board and Merger are under final design.
    - Mass production will start in this year.

Trends of HAPD Production

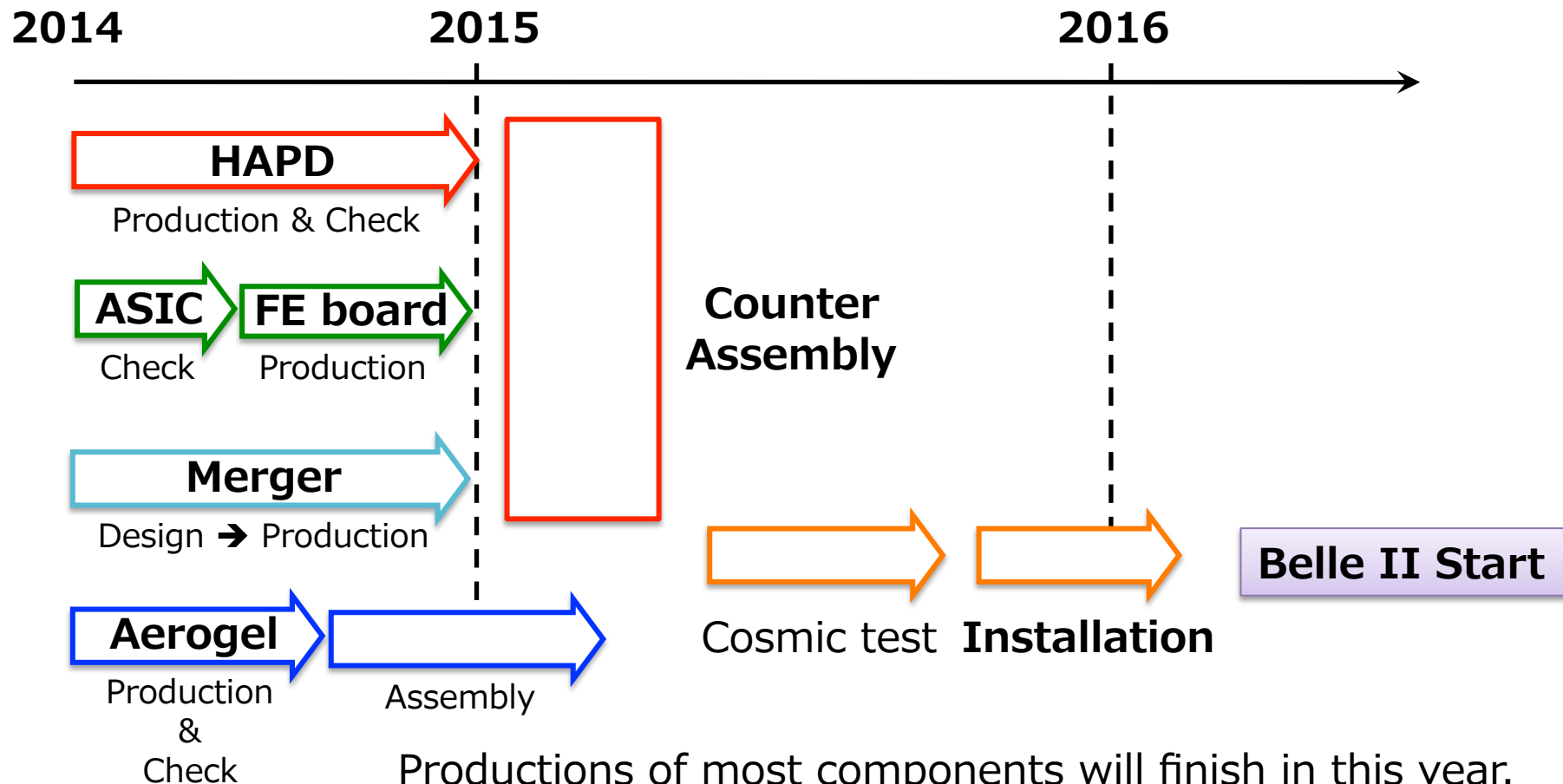


ASIC test system





# Schedule



Productions of most components will finish in this year.  
Counter assembly will start in 2015.  
After counter assembly, we are planning the cosmic test.

# Summary

- The **Belle II** experiment will start from 2016.
- We have been developing **Aerogel RICH (A-RICH)** using 144-ch HAPD for the end-cap PID device.
- We have been producing components of A-RICH.
- **HAPD:**
  - Mass production had been started in 2013.
  - Noise issue are found, further investigation is on-going.
  - Delivery schedule is delayed, it will finish in this year.
- **Readout ASIC:**
  - Mass production had finished → ASICs are under quality check.
- **Other Electronics:**
  - Production of Front-end boards and Merger system will start in this year.
- **All components will be ready** in this year. We will start assembling the A-RICH counter in 2015.

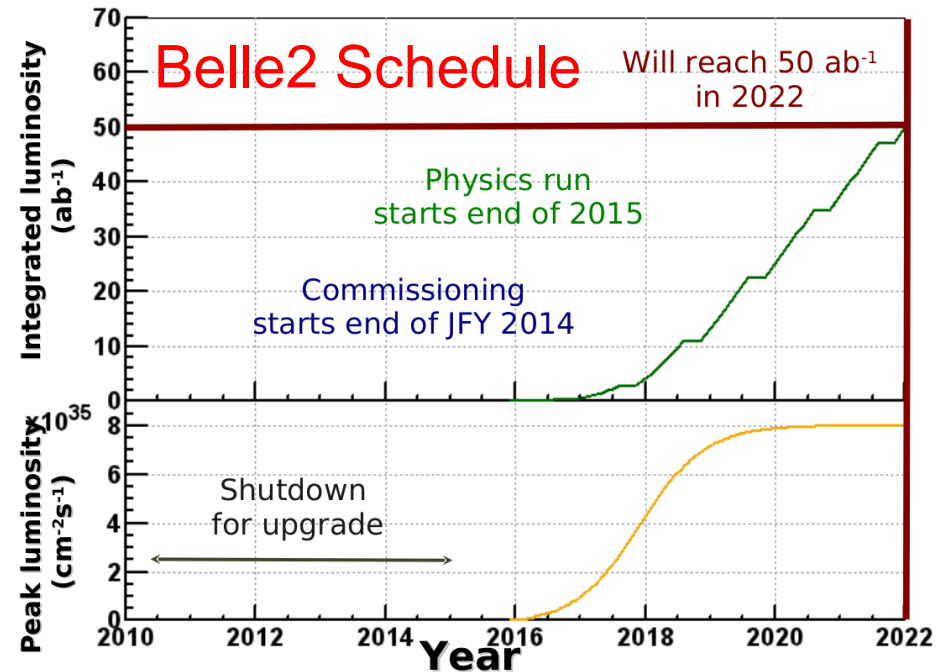
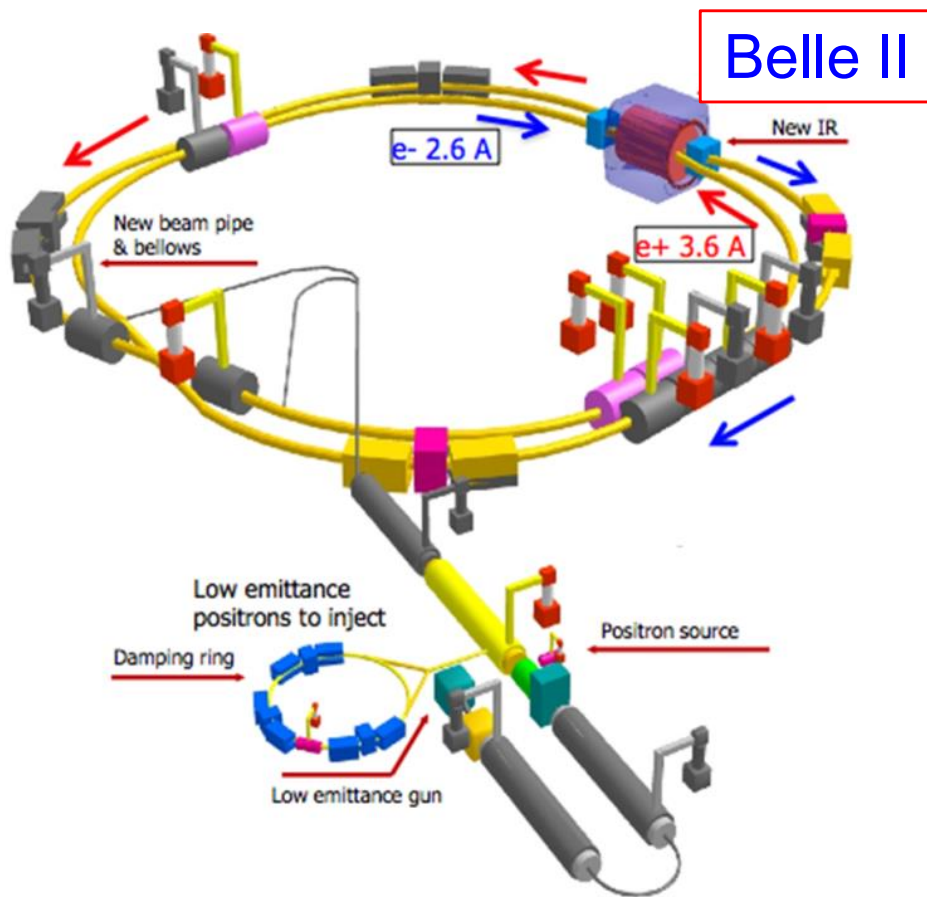
## Plan

- After assembly of the counter, we are planning the cosmic test.
- Installation of A-RICH in the Belle II is in 2015.

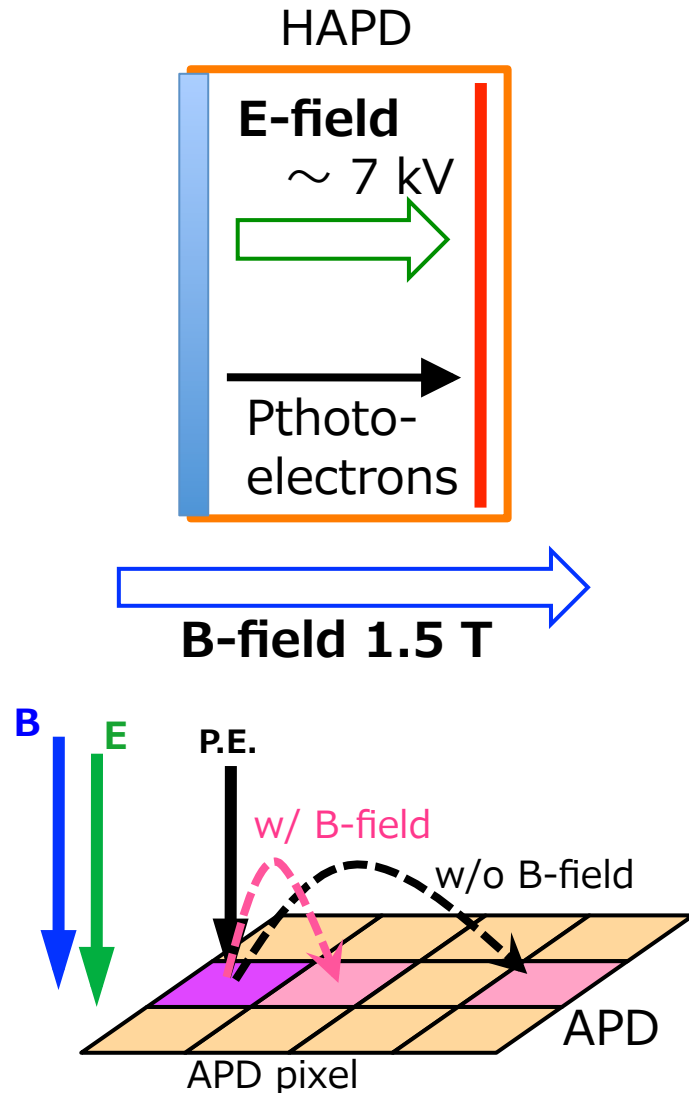


**Back up**

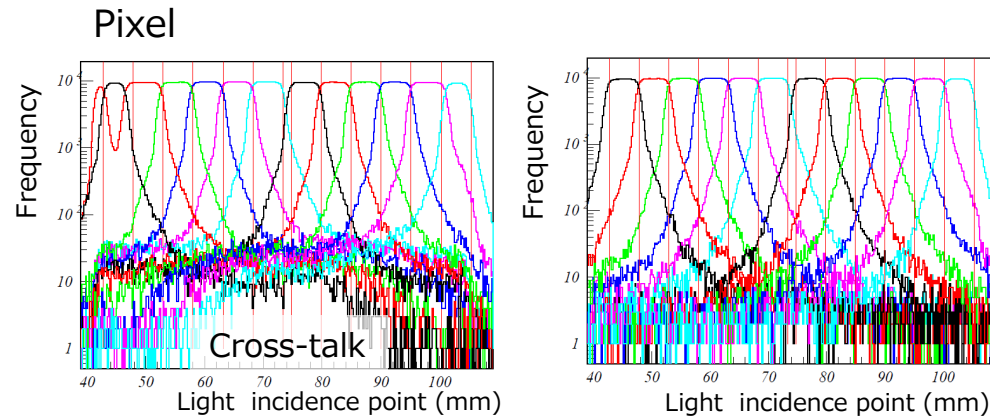
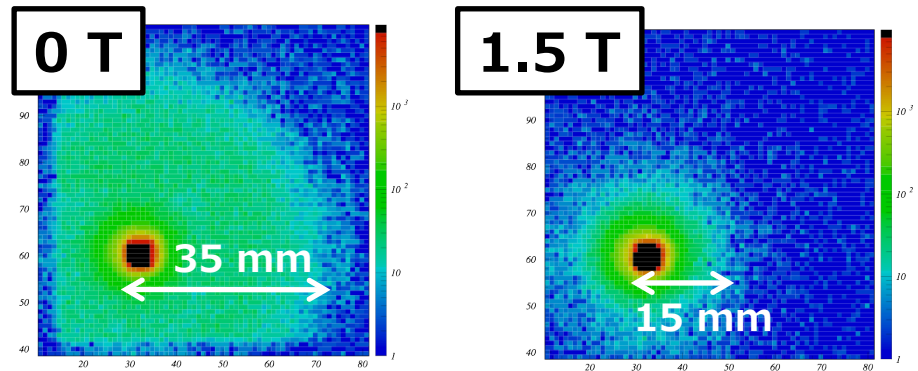
# SuperKEKB accelerator



# Tolerance to Magnetic field



Scattering radius of photoelectrons

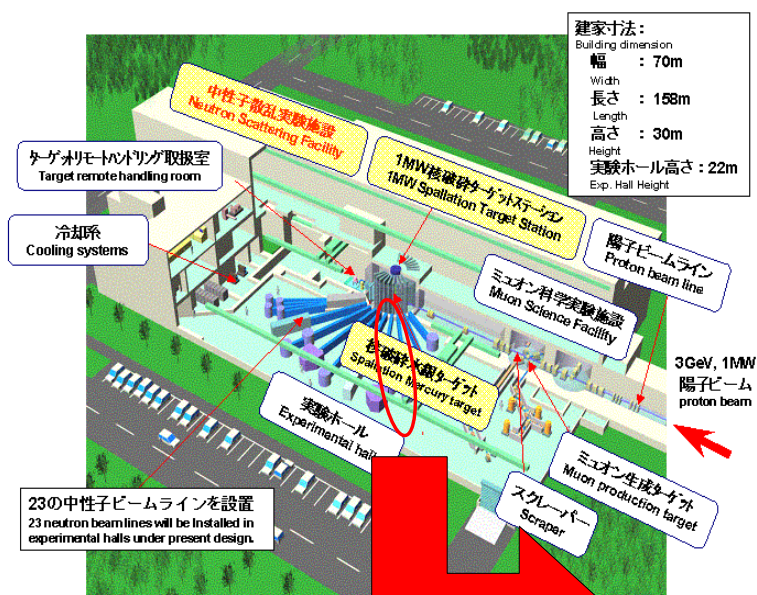


Colored lines show detection efficiency of each channel.

# Neutron Test 2013

## J-PARC MLF

物質・生命科学実験施設 (中性子散乱/ ミュオン科学実験施設)  
Material and Life Science Experimental Facility (Neutron Scattering / Muon Science Facility)



BL10 中性子源  
NeutrOn Beam-line for Observation and

★中性子源施設として自ら責任を持って中性子ビーム性能を把握し、質の高い中性子ビームをユーザーに提供すること

Aerogel radiators  
KA067  
KA086  
KA079  
KA082  
Neutron beam

バンドチョッパー  
前置き遮蔽体  
ビームダクト  
試料位置  
実験テーブル  
入口と通路

BL10

ビームライン番号: BL10 (非結合型モデレータ)  
L1 (モデレータ-試料間距離): 14.0 m  
最大ビーム形状: 100 mm x 100 mm  
実験室空間: 幅2.5 m x 長さ3.5 m x 高さ3.0 m

試料位置での冷中性子束:  $4.8 \times 10^7$  [n/s.cm<sup>2</sup>]  
10 meVのピーク強度:  $1.5 \times 10^{12}$  [n/eV.s.cm<sup>2</sup>]  
10 meVのパルス幅 (FWHM): 33 [ $\mu$ s]  
波長バンド幅: 9 Å (シフト可能)

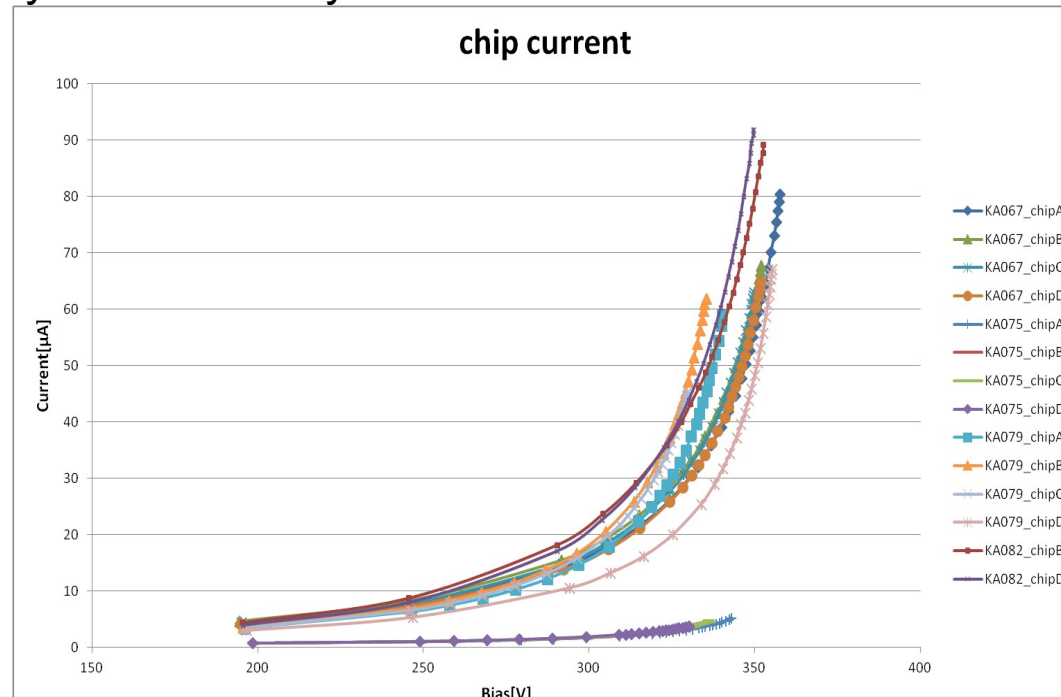


# Gamma-ray Hardness

## Chip Current VS Bias

Bias voltage scan during the irradiation

$\gamma$ -ray dose:  $\sim 950\text{Gy}$



Breakdown is not observed up to maximum bias voltage for all the HAPDs

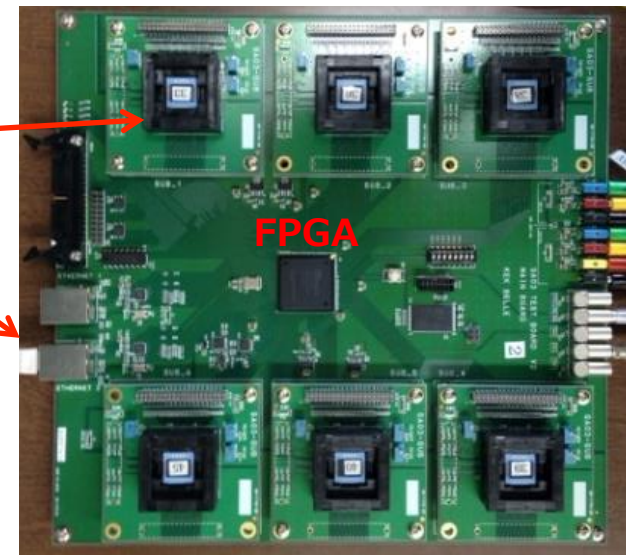
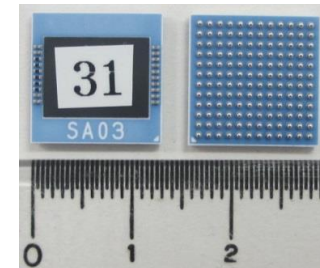
6



# Readout ASIC

- ASICs: 2500 chips
  - Already finished mass production.
  - Quality check is on-going.
  - We developed the **test system** for mass productions.
    - Max. 6 ASICs are available.
    - Adopt removable sockets
    - TCP/IP communication
  - We are preparing automatic test software.

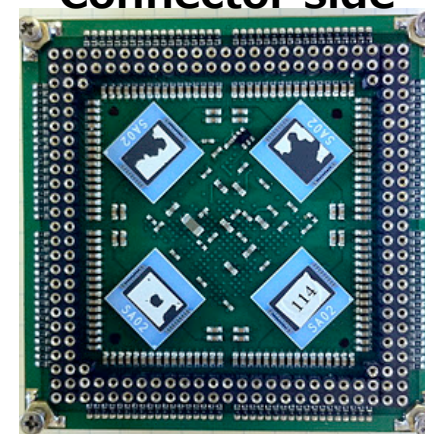
LTCC package



# Front-end Board

- Front-end boards are under final design.
  - 4 ASIC + Xilinx FPGA (Spartan6)
  - Correct hit information from HAPD
  - Set ASIC parameters
  - HAPD bias voltage distribution
- Basic performance are confirmed by beam test.
  - @DESY, 2013
- **Mass production will be start in this year.**

Connector side



Attached on HAPD



# Merger system

- Merger Board: > 72 units
- Specifications are almost fixed
  - Collect hit data from 5~6 FE boards
  - Distribute the trigger
  - Set parameters

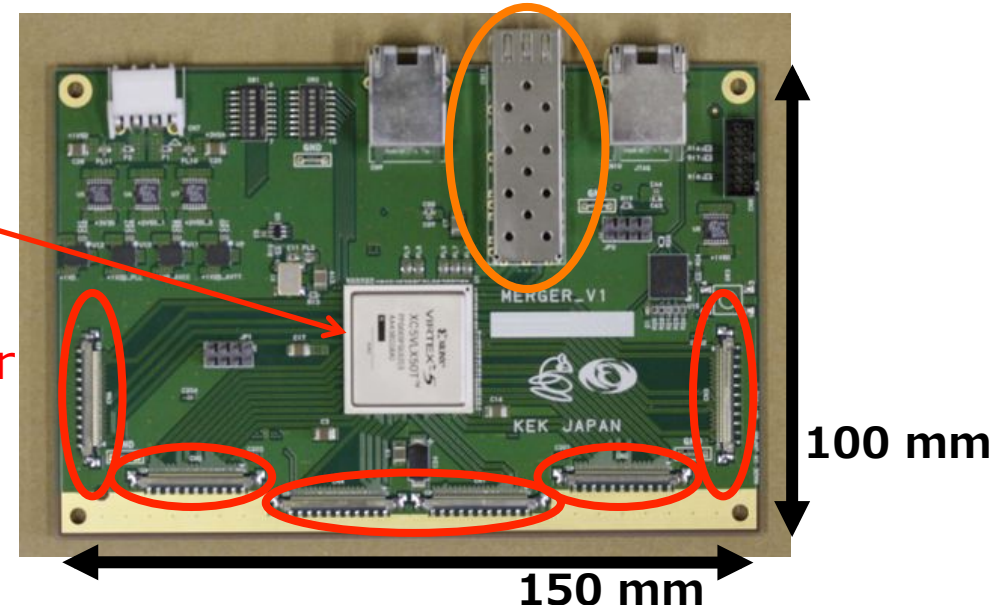
- ✓Data transfer
- ✓Slow control
- ✓Trigger, Clock
- ✓JTAG for FPGA

Optical connector  
→ Belle2Link

## Prototype of Merger Board

FPGA  
(Virtex5)

Interface connector  
for front-ends

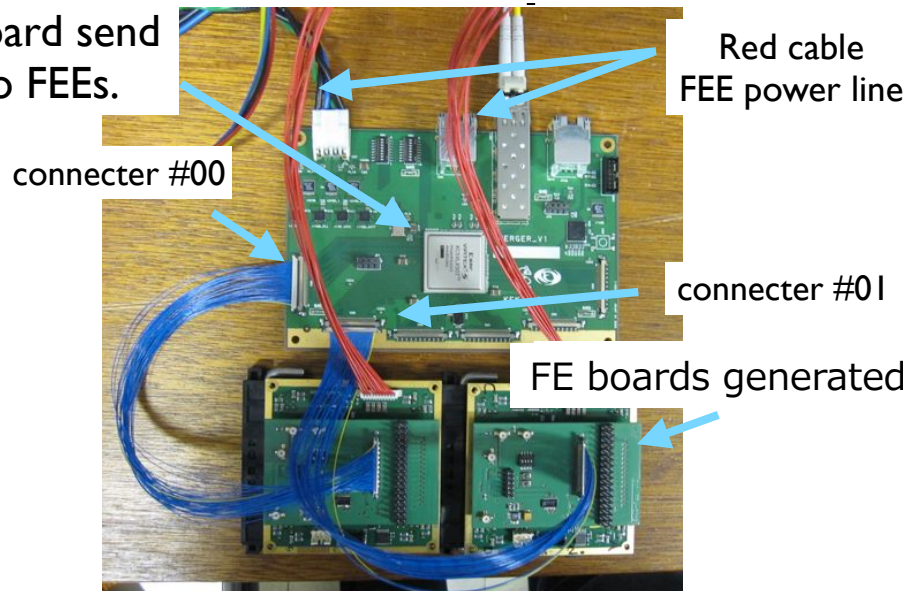


KEK Electronics System group  
has been developing.

# Merger system

- Communication test with Prototype is on-going.
  - Slow control for FE boards by Belle2Link
  - Readout from 1~multi FE board(s)
  - Configuration of FPGA on a FE board

The merger board send a test trigger to FEEs.



Basic functions were confirmed,



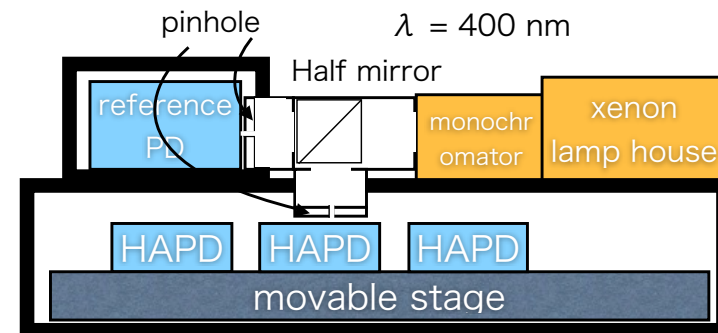
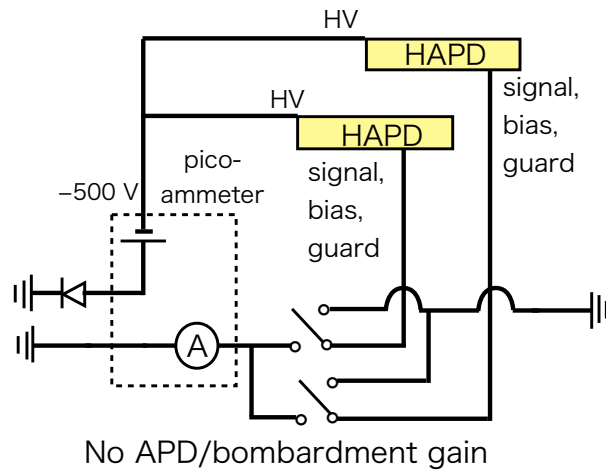
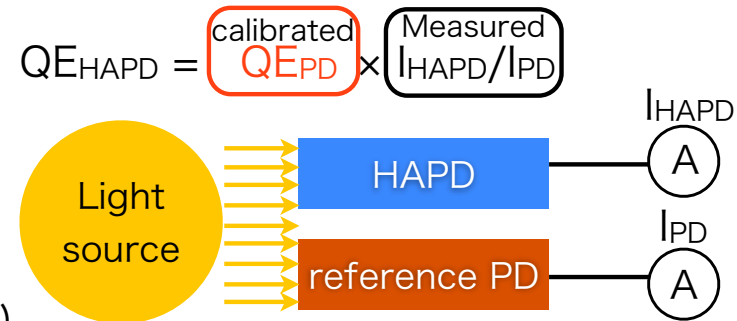
**Mass production had started from April.**

# QE measurement

## Overview of QE measurement system

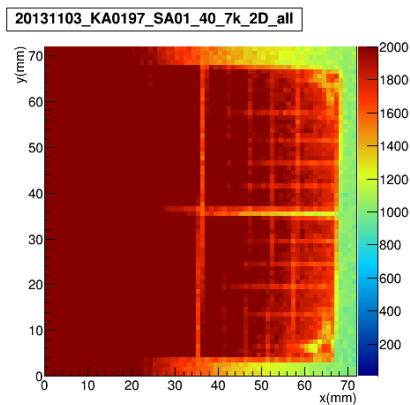
Measure currents of HAPD using pico-ammeter and compare it to that from reference PD.

Move HAPD on the stage and measure current when illuminating ~1 mm size spot light (50 times/point).  
→ 2D QE map on photocathode.



By Y. Yusa  
(Niigata Univ.)

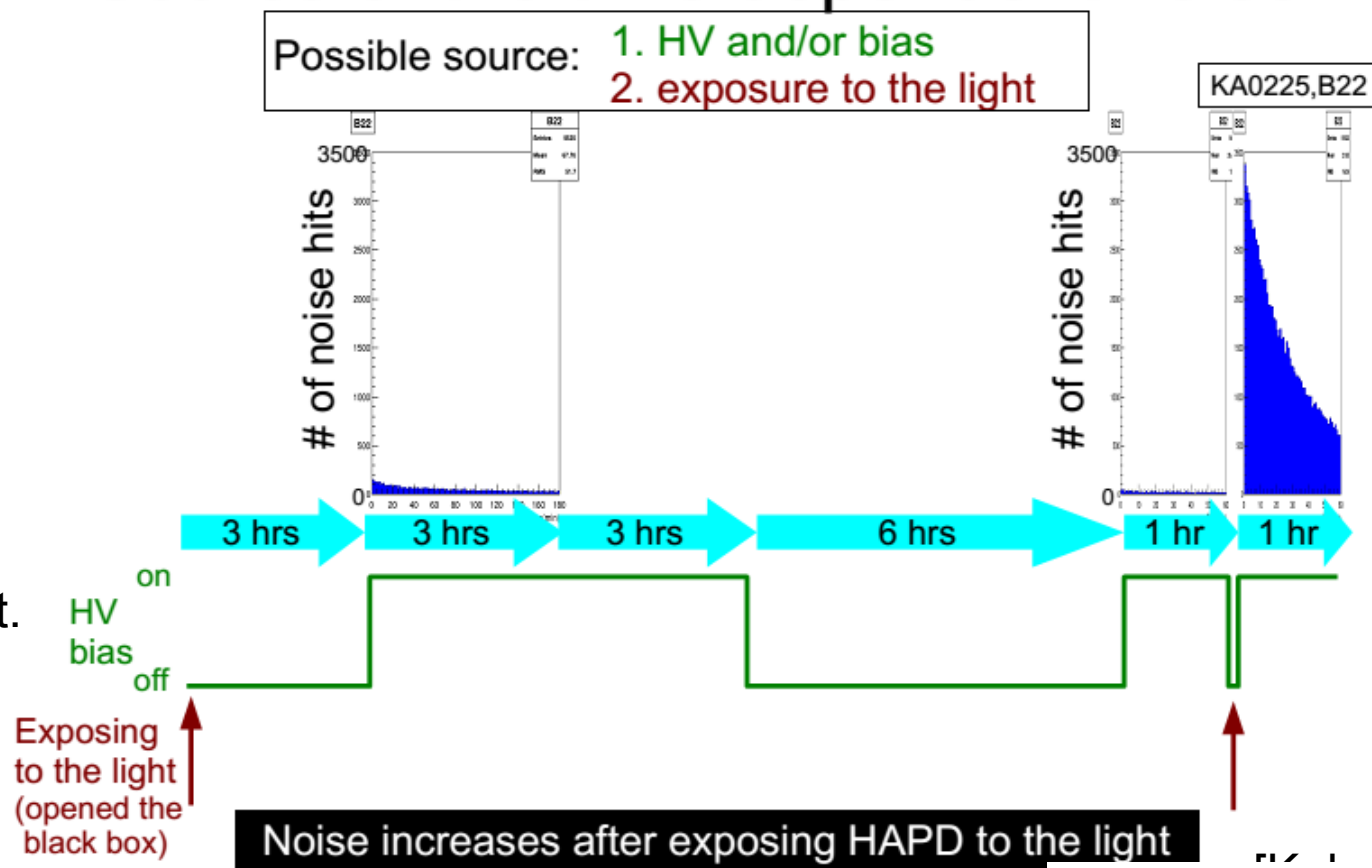
# Noisy HAPD Issue



Seems the problem is related to exposure to light.

## Source of the time dependent noise

Possible source: 1. HV and/or bias  
2. exposure to the light



By H. Kakuno  
(Tokyo Metro. Univ.)

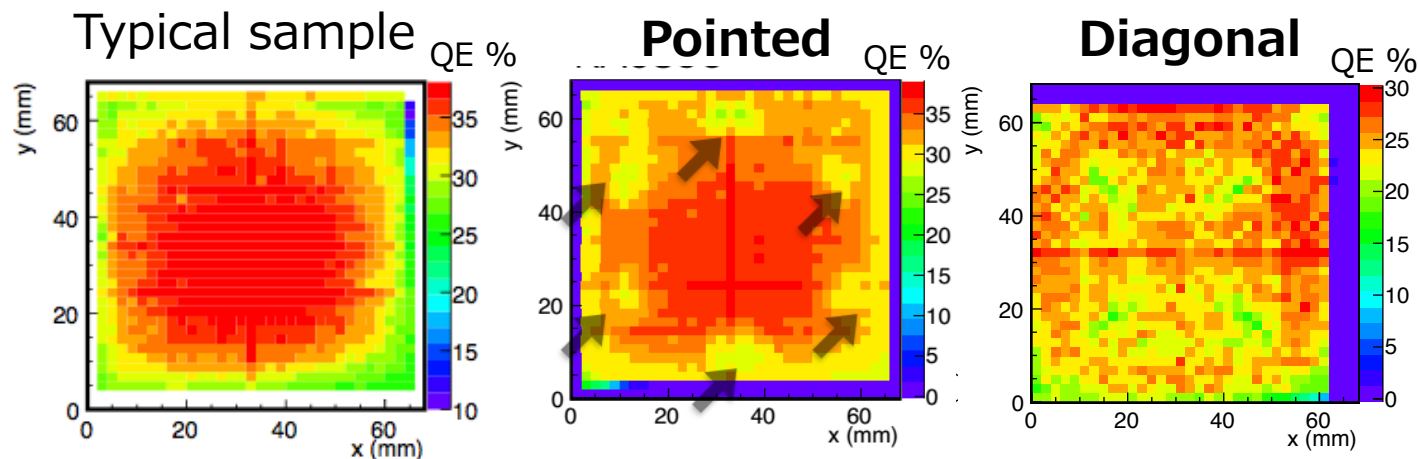


# Investigation for productions

Some troubles are found from some HAPDs.  
They are also investigated by our system.

## ❖ QE 2D Distribution

- We found some samples with **funny structure** of QE by our measurement system.
- This problem is not resolve, we and Hamamatsu Photonics are researching about the detail cause.



Hamamatsu people also observe same structure. They try to understand why this structure appears.